

512 Bit Electrically Alterable Read Only Memory

- 32 Word x 16 Bit Organization
- 5 Bit Binary Addressing
- +5, -28 V Power Supplies
- Word Alterable
- 10 Year Data Storage for ER2051 (at +70°C)
- 1 Year Data Storage for ER2051IR (at +85°C) and ER2051HR (at +125°C)
- TTL Compatibility with Pull-Up Resistors on Inputs
- Tri-State Outputs
- Read Time: 1 μ s (ER2051), 2 μ s (ER2051IR and ER2051HR)
- Write/Erase Time: 50ms (ER2051), 100ms (ER2051HR)
- No Voltage Switching Required
- Chip Select
- Two Extended Temperature Ranges:
 - 40°C to +85°C ER2051IR
 - 55°C to +125°C ER2051HR

DESCRIPTION

The ER2051, ER2051IR and ER2051HR are fully decoded 32 x 16 electrically erasable and reprogrammable ROMs. Write, erase, and read voltages are switched internally via a 2-bit code applied to C1 and C2.

Data is stored by applying negative writing pulses that selectively tunnel charge into the oxide-nitride interface of the gate insulator of the 512 MNOS memory transistors. When the writing voltage is removed the charge trapped at the interface is manifested as a negative shift in the threshold voltage of the selected memory transistors.

The EAROM may be operated with the V_{SS} power supply between +5V and +10Volts, as long as the $V_{SS}-V_{GG}$ always equals 33 Volts. Thus, V_{SS} can be +5Volts for TTL compatibility or up to +10Volts for CMOS compatibility, if V_{GG} is appropriately adjusted. The ER2051IR and ER2051HR are screened to Mil Std. 883B/ method 5004.1/level B, pre-cap visual inspection, environmental testing, burn-in and external visual. They are available in 28 lead ceramic dual in line packages.

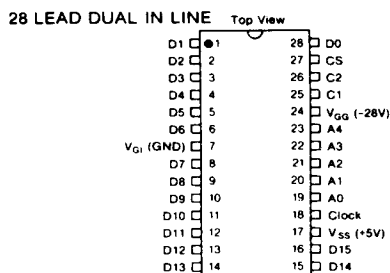
OPERATION

Data is stored in a two transistor memory cell. After the cell is preconditioned by an erase signal (which causes a positive shift in the threshold of both transistors), data is written into one of the transistors making its threshold more negative. A sensing flip flop is used to read the memory cell and presents a logic high or low to the output depending upon which transistor is written.

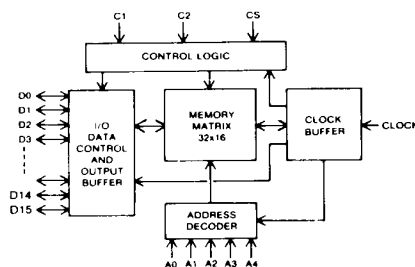
PIN FUNCTIONS

Pin No	Name	Function
19, 20, 21, 22 1-6, 8-14, 28 27	A_0-A_4 D_0-D_{15} CS	5-Bit Word Address. Data input and output pins. Chip Select. Chip selected at logic "1". When chip select is at logic "0", outputs are open circuit, read, write and erase are disabled. Power is reduced.
25, 26	C1, C2	Mode Control Inputs. C1 C2 0 1 Erase Mode: stored data is erased at addressed location. 1 Don't Care Read Mode: addressed data read after clock pulse. Output data retained at output pins until chip deselected or control lines switched. 0 0 Write Mode: input data written at addressed location. Clock not required.
18	CLK	Clock input. Pulse to logic "1" for read operation.
17	V_{SS}	Substrate supply. Normally at +5 volts.
7	V_{GI}	Ground Input.
24	V_{GG}	Power Supply Input. Normally at -28 volts.

PIN CONFIGURATION



BLOCK DIAGRAM



It is important to note two things: first, that an erase is required before a wire to precondition the cell, and second, that after an erase, both transistors will have the same threshold voltage and valid data will not be present at the output.

The ER2051, ER2051IR and ER2051HR EAROM's use internal dynamic, edge triggered circuits. This requires either a mode change, a clock, or a transition of the chip select between successive operations. Thus successive operations in the same mode must be separated by transitions of one of these four lines. Clock pulses are not normally required during erase or write operations, but are needed for successive operations if the chip select is held high, i.e., applications where one EAROM is used.

ELECTRICAL CHARACTERISTICS**Maximum Ratings***

All Inputs and Outputs (with Respect to V_{SS}) -35V to +0.3V
 Storage Temperature -65°C to +150°C
 Soldering Temperature of Leads (10 seconds) +300°C

Standard Conditions (for TTL compatibility) $V_{SS} = +5V \pm 5\%$ $V_{GG} = -28V \pm 5\%$ $V_{GI} = GND$ Operating Temperature $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ for ER2051 $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$ for ER2051 IR $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ for ER2051 HR

Output Load = 100pf, 1 TTL load

* Exceeding these ratings could cause permanent damage to the device. This is a stress rating only and functional operation of this device at these conditions is not implied—operating ranges are specified in Standard Conditions. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Data labeled "typical" is presented for design guidance only and is not guaranteed.

Characteristics	Sym	ER2051			ER2051 IR/ER2051 HR			Units	Conditions
		Min.	Typ.**	Max.	Min.	Typ.**	Max.		
DC CHARACTERISTICS									
Input Logic "1"	V _{IH}	V _{SS} - 1.5	—	V _{SS} + 0.3	V _{SS} - 1.5	—	V _{SS} + 0.3	V	I _{OH} = 100μA I _{OL} = 1.6mA for V _{SS} = +5V V _{IN} = V _{SS} - 15 Chip deselected
Input Logic "0"	V _{IL}	V _{SS} - 15	—	0.8	V _{SS} - 10	—	0.6	V	
Output Logic "1"	V _{OH}	V _{SS} - 1.5	—	—	V _{SS} - 1.5	—	—	V	
Output Logic "0"	V _{OL}	—	—	0.6	—	—	0.6	V	
Input Leakage	I _L	—	2	10	—	2	10	μA	
Output Leakage	I _O	—	2	10	—	2	10	μA	
Power Supply Current									
Read	I _{GG}	—	—	14	—	—	18	mA	I _{GG} returned through V _{SS}
Write	I _{GG}	—	—	11	—	—	15	mA	
Erase	I _{GG}	—	—	11	—	—	15	mA	
Deselected	I _{GG}	—	—	9	—	—	12	mA	
AC CHARACTERISTICS									
Access Time	t _{ACC}	—	—	1	—	—	2	μs	at max temperature at 25°C V _{SS} = +5, V _{GG} = -29 at 125°C V _{SS} = +5, V _{GG} = -29 at -55°C V _{SS} = +5, V _{GG} = -29
Clock Pulse Width	t _{PW}	2	—	20	2	—	20	μs	
Erase Cycle Time	t _E	50	—	200	100	—	200	ms	
Write Cycle Time	t _W	50	—	200	100	—	200	ms	
Read Cycle Time	t _R	3.5	—	24	4.5	—	25	μs	
Address to Clock Time	t _A	50	—	—	50	—	—	ns	
Data Set Up Time	t _{DS}	50	—	—	50	—	—	ns	
Data Hold Time	t _{DH}	50	—	—	50	—	—	ns	
Control to Address & Data Change	t _C	0	—	—	0	—	—	ns	
Number of Reads/Word Refresh	N _{RA}	10 ¹¹	—	—	10 ¹¹	—	—	—	
Number of Erase/Write Cycles	N _W	10 ⁶	—	—	10 ⁵	—	—	—	
Input Capacitance (all pins)	C _{IO}	—	8	15	—	8	15	pf	
Unpowered Data Storage Time	t _S	10	—	—	1	—	—	Years	
Power Dissipation Read Cycle	P _D	—	450	500	—	450	500	mW	
	P _D	not applicable			—	—	500	mW	
	P _D	not applicable			—	—	600	mW	
Pulse Rise, Fall Time	t _r , t _f	10	—	100	10	—	100	ns	

**Typical values are at $+25^\circ\text{C}$ and nominal voltages.

TIMING DIAGRAM

